

31. The device in accordance with claim 14, wherein said X-ray beam tube and said detector are adapted to move parallel to the at least one test object.

32. A process of inspecting at least one test object with an apparatus that includes an X-ray beam tube having a small field of view in relation to a horizontal extent of an area of the test objects to be inspected, and a detector having a small field of view in relation to the horizontal extent of the area of the test objects to be inspected, the process comprising:

fixedly mounting the at least one test object;

moving the X-ray beam tube and the detector within an X-Y plane, thereby inspecting an entire area of the at least one test object.

33. The process in accordance with claim 32, further comprising moving the X-ray beam tube and the detector parallel to each other.

34. The process in accordance with claim 33, further comprising moving the X-ray beam tube and the detector together in a same direction.

35. The process in accordance with claim 33, further comprising moving the X-ray beam tube and the detector a same direction.

36. The process in accordance with claim 33, further comprising moving the X-ray beam tube and the detector in opposite directions.

37. The process in accordance with claim 32, further comprising moving the X-ray beam tube and the detector parallel to the at least one test object.---

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IN THE ABSTRACT

Please substitute the following Abstract for the Abstract contained in the application:

---ABSTRACT OF THE DISCLOSURE

Device and process for inspecting at least one test object. The device includes an X-ray beam tube having a small field of view in relation to a horizontal extent of an area of the at least one test object to be inspected, and a detector having a small field of view in relation to the horizontal extent of the area of the at least one test object to be inspected. The at least one test object is stationary during the inspection, and the X-ray beam tube and the detector are moveably arranged within an X-Y plane for inspecting an entire area of the at least one test object. The process includes fixedly mounting the at least one test object, and moving the X-ray beam tube and the detector within an X-Y plane, thereby inspecting an entire area of the at least one test object.---